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 Members of the Texas Instruments Widebus[™] Family 	SN54ABT16952 WD PACKAGE SN74ABT16952 DGG OR DL PACKAGE (TOP VIEW)	
 State-of-the-Art <i>EPIC</i>-IIB[™] BiCMOS Design Significantly Reduces Power Dissipation 		
 Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17 	1CLKAB 2 55 1CLKBA 1CLKENAB 3 54 1CLKENBA	
 Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C 	GND 4 53 GND 1A1 5 52 1B1	
 Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise 	1A2 6 51 1B2 V _{CC} 7 50 V _{CC}	
 Flow-Through Architecture Optimizes PCB Layout 	1A3 8 49 1B3 1A4 9 48 1B4 1A5 10 47 1B5	
 High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OL}) 	1A5 [] 10 47 [] 1B5 GND [] 11 46 [] GND	
Package Options Include Plastic 300-mil Shrink Small Outline (DL) and Thin Shrink	1A6 [12 45] 1B6	
Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil	1A7 [] 13 44 [] 1B7 1A8 [] 14 43 [] 1B8	
Fine-Pitch Ceramic Flat (WD) Package	2A1 [15 42] 2B1	
Using 25-mil Center-to-Center Spacings	2A2 🛛 16 🛛 41 🗋 2B2	
description		
•	GND 18 39 GND 2A4 19 38 2B4	
The 'ABT16952 are 16-bit registered transceivers that contain two sets of D-type flip-flops for	2A4 [] 19 38 [] 2B4 2A5 [] 20 37 [] 2B5	
temporary storage of data flowing in either	2A6 21 36 2B6	

that contain two sets of D-type flip-flops for temporary storage of data flowing in either direction. The 'ABT16952 can be used as two 8-bit transceivers or one 16-bit transceiver. Data on the A or B bus is stored in the registers on the low-to-high transition of the clock (CLKAB or CLKBA) input provided that the clock-enable (CLKENAB or CLKENBA) input is low. Taking the output-enable (OEAB or OEBA) input low accesses the data on either port.

4				
	2A3 [17	40] 2B3
G	ND [18	39] GND
	2A4 [19	38] 2B4
	2A5 [20	37] 2B5
	2A6 [21	36] 2B6
١	/ _{cc} [22	35] v _{cc}
	2A7 [23	34] 2B7
	2A8 [24	33] 2B8
G	IND [25	32] GND
2CLKEN	IAB [26	31	2CLKENBA
2CLk	кав [27	30] 2CLKBA
2OE	AB [28	29	20EBA

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16952 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT16952 is characterized for operation from –40°C to 85°C.



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SN54ABT16952, SN74ABT16952 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS SCBS082C - FEBRUARY 1991 - REVISED JANUARY 1997

FUNCTION TABLE[†]

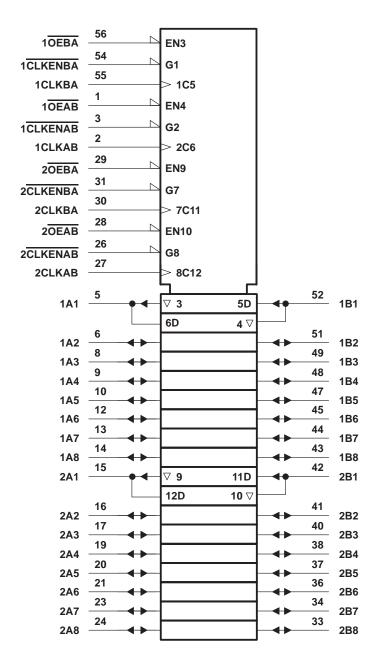
	INPUTS									
CLKENAB	CLKAB	OEAB	Α	В						
н	Х	L	Х	в ₀ ‡ в ₀ ‡						
Х	L	L	Х	в ₀ ‡						
L	\uparrow	L	L	L						
L	\uparrow	L	Н	н						
Х	Х	Н	Х	Z						

[†] A-to-B data flow is shown; B-to-A data flow is similar, but uses CLKENBA, CLKBA, and OEBA.

‡Level of B before the indicated steady-state input conditions were established



logic symbol[†]

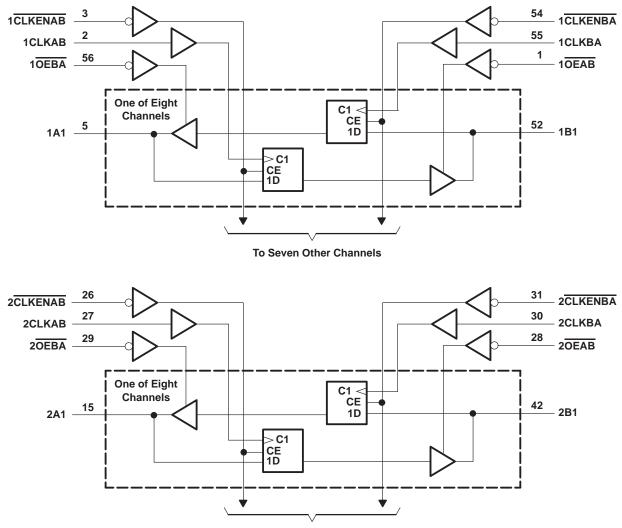


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



To Seven Other Channels



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} Input voltage range, V_I (except I/O ports) (see Note 1) Voltage range applied to any output in the high or power-off state, V_O Current into any output in the low state, I_O : SN54ABT16952 SN74ABT16952 Input clamp current, I_{IK} ($V_I < 0$) Output clamp current, I_{OK} ($V_O < 0$) Package thermal impedance, θ_{JA} (see Note 2): DGG package	0.5 V to 7 V 0.5 V to 5.5 V
DL package	
e e e e e e e e e e e e e e e e e e e	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

		SN54ABT	16952	SN74AB1			
			MIN	MAX	MIN	MAX	
Vcc	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	High-level input voltage		2	EW	2		V
VIL	Low-level input voltage					0.8	V
VI	Input voltage		0 0	Vcc	0	VCC	V
ЮН	High-level output current		C,	-24		-32	mA
I _{OL}	Low-level output current		202	48		64	mA
$\Delta t / \Delta v$	Input transition rise or fall rate	Outputs enabled	4	10		10	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST CONDITIONS		Т	A = 25°C	;	SN54AB	T16952	SN74ABT16952			
PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT	
VIK		V _{CC} = 4.5 V,	lj = -18 mA			-1.2		-1.2		-1.2	V	
		$V_{CC} = 4.5 V,$	I _{OH} = -3 mA	2.5			2.5		2.5			
Marri	$V_{CC} = 5 V,$	I _{OH} = -3 mA	3			3		3		V		
∨он		V _{CC} = 4.5 V	I _{OH} = -24 mA	2			2				v	
		VCC = 4.5 V	I _{OH} = -32 mA	2*					2			
VOL		V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			v	
VOL		VCC = 4.5 V	I _{OL} = 64 mA			0.55*				0.55		
V _{hys}					100			2			mV	
ŧ	Control inputs	V _{CC} = 5.5 V,	VI = V _{CC} or GND			±1		L/±1		±1	μA	
Ч	A or B ports $VCC = 5.5 \text{ v},$					±100		<u>/</u> ±100		±100	μΑ	
IOZH‡		V _{CC} = 5.5 V,	V _O = 2.7 V			50	4	50		50	μΑ	
Iozl‡		V _{CC} = 5.5 V,	$V_{O} = 0.5 V$			-50	5	-50		-50	μΑ	
loff		$V_{CC} = 0,$	V_I or $V_O \leq 4.5~V$			±100	00			±100	μΑ	
ICEX		V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50	PP	50		50	μΑ	
١٥	_	V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-100	-200	-50	-200	-50	-200	mA	
		V _{CC} = 5.5 V,	Outputs high			2		2		2		
ICC		$I_{O} = 0,$	Outputs low			35		35		35	mA	
		Outputs disabled			2		2		2			
∆ICC¶		$V_{CC} = 5.5 V$, One is Other inputs at V_{CC}				0.5		0.5		0.5	mA	
Ci	Control inputs	$V_I = 2.5 \text{ V or } 0.5 \text{ V}$			3						pF	
Cio	A or B ports	$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$	/		8.5						pF	

* On products compliant to MIL-PRF-38535, this parameter does not apply.

[†] All typical values are at $V_{CC} = 5$ V.

[‡] The parameters I_{OZH} and I_{OZL} include the input leakage current.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 \P This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			V _{CC} = 5 V, T _A = 25°C		$\begin{array}{c c} V_{CC} = 5 V, \\ T_A = 25^{\circ}C \end{array} SN$		SN54ABT16952		2 SN74ABT16952		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX			
fclock	Clock frequency	0	150	0	150	0	150	MHz			
tw†	Pulse duration, CLKAB or CLKBA high or low		3.3		3.3	25	3.3		ns		
	Setup time,	A or B	3.5		3.5		3.5				
t _{su}	before CLKAB↑ or CLKBA↑	CLKENAB or CLKENBA	3		3		3		ns		
+.	Hold time,	A or B	1		01		1		20		
Чh	^t h after CLKAB↑ or CLKBA↑	CLKENAB or CLKENBA	1		2 1		1		ns		

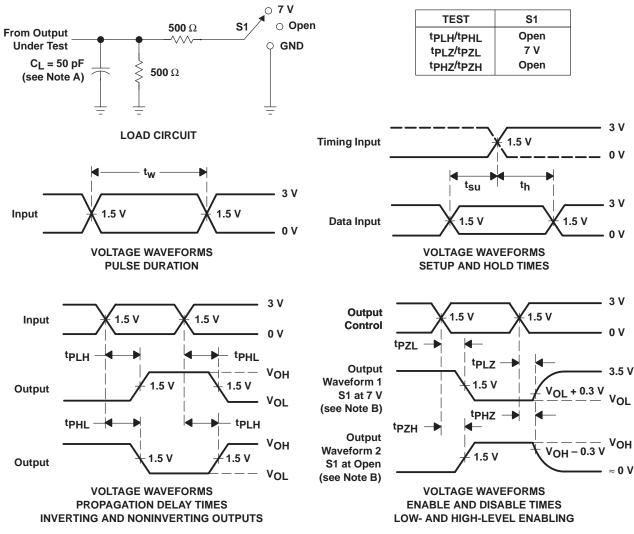
[†] This parameter is warranted, but not production tested.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V(Tj	CC = 5 V A = 25°C	, ;	SN54AB1	16952	SN74ABT	16952	UNIT
		(001-01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
fmax			150			150	M	150		MHz
^t PLH	CLK	A or B	1	2.6	3.9	1	\$4.4	1	4.3	ns
^t PHL	OLK		1	2.6	4.2	1	4.6	1	4.5	
^t PZH	OE	A or B	1	2.5	3.8	1	4.7	1	4.6	20
^t PZL	ÛE	AUB	1	2.8	5.1	5	6.1	1	6	ns
^t PHZ	OE	A or B	1.7	3.4	4.7	01.7	6.1	1.7	5.5	
^t PLZ	ÛE	AOIB	1.3	3	3.9	Q 1.3	4.8	1.3	4.2	ns



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.

D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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